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Docket No.: M0025.0340/P340 (PATENT)

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of: Yao-Chun Shen et al.

Application No.: 10/550,620

Confirmation No.: 4660

Filed: September 26, 2005

Art Unit: N/A

For: TERAHERTZ RADIATION SOURCES

AND METHODS

Examiner: Not Yet Assigned

## INFORMATION DISCLOSURE STATEMENT (IDS)

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Pursuant to 37 CFR 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO/SB/08. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is filed before the mailing date of a first Office Action on the merits as far as is known to the undersigned (37 CFR 1.97(b)(3)).

Applicant has not submitted copies of each cited U.S. patent and U.S. patent application as required by 37 CFR 1.98(a)(2)(i), amended October 2004, as the U.S.

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Patent and Trademark Office has waived this requirement for all U.S. patent applications. Applicant submits herewith copies of foreign and non-patents in accordance with 37 CFR 1.98(a)(2).

In accordance with 37 CFR 1.97(g), the filing of this Information Disclosure Statement shall not be construed to mean that a search has been made or that no other material information as defined in 37 CFR 1.56(a) exists. In accordance with 37 CFR 1.97(h), the filing of this Information Disclosure statement shall not be construed to be an admission that any patent, publication or other information referred to therein is "prior art" for this invention unless specifically designated as such.

It is submitted that the Information Disclosure Statement is in compliance with 37 CFR 1.98 and the Examiner is respectfully requested to consider the listed references.

The Director is hereby authorized to charge any deficiency in the fees filed, asserted to be filed or which should have been filed herewith (or with any paper hereafter filed in this application by this firm) to our Deposit Account No. 04-1073, under Order No. M0025.0340/P340.

Dated: June 30, 2006

Respectfully submitted,

Stephen A. Soffen

Registration No.: 31,063

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## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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	Complete if Known	
Application Number	10/550,620-Conf. #4660	
Filing Date	September 26, 2005	
First Named Inventor	Yao-Chun Shen	
Art Unit	N/A	
Examiner Name	Not Yet Assigned	
Attorney Docket Number	M0025.0340/P340	

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Application Number 10/550,620-Conf. #4660		
			CLOSURE	Filing Date September 26, 2005 First Named Inventor Yao-Chun Shen		
			PPLICANT			
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